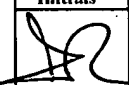




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			Application Number	10/510,916
			Confirmation Number	7320
			Filing Date	October 12, 2004
			First Named Inventor	Shinichi ISHIBASHI
			Art Unit	2812
Sheet 1 of 1			Examiner Name	Not yet assigned
			Attorney Docket Number	Q84137

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
		US			
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		US			
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			

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		SHINJI TSUBOI, et al., Recent progress in 1Xx-ray mask technology: Feasibility Study using ASET-NIST format TaXN x-ray masks with 100 nm rule 4 Gbit dynamic random access memory test patterns, 2001 American Society, pgs. 2416-2422.	
		M. TAKAHASHI, et al., Smooth, low-stress, sputtered tantalum and tantalum alloy films for the absorber material of reflective-type EUVL, In Emerging Lithographic Technologies IV, Elizabeth A. Dabisz, Editor, Proceedings of SPIE Vol. 3997 (2000), pgs. 484-495.	
		KENNETH RACETTE, et al., Sputter deposition and annealing of Ta, TaSi <sub>x</sub> and TaB <sub>x</sub> composite films and their application in next generation lithography masks, 2000 American Vacuum Society, pgs. 1119-1124.	

Examiner Signature		Date Considered	12/07
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# **INFORMATION DISCLOSURE STATEMENT BY APPLICANT** ( Not for submission under 37 CFR 1.99)

Application Number	10510916
Filing Date	2004-10-12
First Named Inventor	Shinichi ISHIBASHI
Art Unit	2812
Examiner Name	
Attorney Docket Number	Q84137

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<i>AB</i>	1	2002-246299	JP	A	2002-08-30	Oki Electric Ind Co Ltd		<input type="checkbox"/>
<i>AB</i>	2	2000-150364	JP	A	2000-05-30	Hoya Corp		<input type="checkbox"/>
<i>AB</i>	3	8-213303	JP		1996-08-20	Nippon Kogaku Kk		<input type="checkbox"/>

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STATEMENT BY APPLICANT**  
( Not for submission under 37 CFR 1.99)

Application Number	10510916
Filing Date	2004-10-12
First Named Inventor	Shinichi ISHIBASHI
Art Unit	2812
Examiner Name	
Attorney Docket Number	Q84137

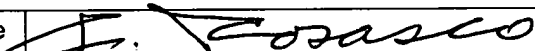
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Application Number	10/510,916
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		Number	Kind Code <sup>2</sup> (if known)		
		US 5,754,619	A	05/19/1998	NEC Corporation
		US			
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		US			
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		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)			
		JP	2002-246299	A	08/30/2002	Oki Electric Industry Co., Ltd.	
		JP	2001-237174	A	08/31/2001	Oki Electric Industry Co., Ltd	
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		JP	7-333829	A	12/22/1995	Hitachi Ltd.	

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		Notification of Transmittal of copies of Translation of the International Preliminary Examination Report	
		PCT Gazette - Section II -Corrected Versions of Pamphlets - February 24, 2005	

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